

4.3 Technical Specifications

Range of thicknesses: 100 to 500,000 angstroms

Spot sizes: 50 um with 5X objective
 25 um with 10X objective
 6.5 um with 40X objective
 2.5 um with 100X objective (optional)

Statistical data accumulation

DataLink communication (SECS II compatible)

Film types:	Oxide on Silicon;	Nitride on Silicon;
	Negative Resist on Silicon;	Polysilicon on Oxide;
	Negative Resist on Oxide;	Nitride on Oxide;
	Thin Oxide on Silicon;	Thin Nitride on Silicon;
	Polyimide on Silicon;	Positive Resist on Silicon;
	Positive Resist on Oxide;	Reflectance Mode;
	Thick Films	EPA914EZ Photo Resist
	Very Thin Oxide (VT only)	Very Thin Nitride (VT only)

Reproducibility: 5A ±5% depending upon the Film Type

Typical measurement time: 2.5 seconds

Power dissipation: 250 watts

Primary power: 117 volts ac ±5% @ 50/60 Hz
 Isolated line free of surges or pulses

Ambient Temperature: 50 to 90 degrees F
 10 to 32 degrees C

Temperature variation: ±3 degrees F (±2 degrees C)

Humidity: maximum 90%

Dimensions:

	Inches			Centimeters		
	H	W	D	H	W	D
Microscope and spectrophotometer	30-5/8	24-1/2	20	77.79	62.23	50.88
Computer	9-1/2	7-1/2	21-1/2	24.13	19.05	54.61
Clean room printer	3-1/16	7-3/8	6-1/2	7.94	18.73	16.51
CRT Terminal	14	13-1/2	13-1/2	35.56	34.29	34.29
Keyboard	2	18-1/2	8	5.08	46.99	20.32
Chart Recorder	4-3/4	9	10-1/2	12.07	22.86	26.69

Weight:

Microscope & spectrophotometer	51	pounds
Computer	20	pounds
Clean room printer	3.5	pounds
CRT Terminal	20.2	pounds
Keyboard	3.2	pounds
Chart Recorder	7.5	pounds

Clearance must be sufficient at rear for routing cables.